

## REMARKS

Claims 1-7 are pending. Claims 1-7 are rejected. Claims 2 and 4 have been amended. No new matter has been added.

### Drawings

The objections to the drawings outlined in the outstanding Office Action by the Examiner have been noted. Formal drawings will be submitted upon allowance of the instant Application.

### Specification

The specification has been amended to overcome the objections to the specification outlined by the Examiner in the outstanding Office Action. The Applicants respectfully request the withdrawal of the objection to the specification.

### Claim Objections

The Claims have been amended to overcome the objections to the Claims outlined by the Examiner in the outstanding Office Action. Consequently, the Applicants respectfully request the withdrawal of the objection to the Claims.

### 112 rejections

The Claims have been amended to overcome the 112 rejections of the Claims outlined by the Examiner in the outstanding Office Action. Consequently, the Applicants respectfully request the withdrawal of the 112 rejections of the Claims. It should be appreciated that Claim 1 is drawn to an apparatus for testing an integrated circuit. The language of Claim 1 clearly and distinctly sets forth the components of the recited apparatus meeting the

requirements of 35 USC 112. As the requirements of 35 USC 112 are met, the Applicants respectfully submit that the 112 rejection of Claim 1 is improper and should be withdrawn.

103 Rejection

Claims 1-7 are rejected under 35 U.S.C. § 103(a) as being unpatentable over Turnquist et al. The Applicants have reviewed the cited reference and respectfully submit that the present invention as is set forth in Claims 1-7 is not either anticipated or rendered obvious by Turnquist et al.

The Examiner is respectfully directed to independent Claim 1, which recites that embodiments of the present invention are directed to an apparatus for testing and integrated circuit comprising:

...a data source coupled to provide test signals to an integrated circuit being tested; a plurality of relays selectively connecting the integrated circuit being tested to the apparatus; a plurality of fan out elements coupled to receive data pulses from the relays and to distribute the data pulses to a plurality of latches; and a strobe element associated with each latch thereby enabling each latch to transfer the data pulses from an input port to an output port of each latch.

Independent Claim 4 recites limitations similar to those found in Claim 1. Claims 2 and 3 depend from Claim 1 and recite further limitations of the claimed invention. Claims 5-7 depend from Claim 4 and recite further limitations of the claimed invention.

Turnquist et al. does not anticipate or render obvious an apparatus for testing and integrated circuit comprising, “a plurality of fan out elements coupled to receive data pulses from the relays and to distribute the data pulses to a plurality of latches” as is recited in Claim 1. Turnquist et al. merely shows an event based semiconductor test system. Nowhere

in Turnquist et al. is there shown fan out elements receiving data pulses from the integrated circuit being tested and connected to distribute data pulses to a plurality of latches as is recited in Claims 1 and 4. Consequently, Turnquist et al. does not anticipate or render obvious the invention as is recited in independent Claims 1 and 4.

Therefore, Applicants respectfully submit that Turnquist et al. does not anticipate or render obvious the present claimed invention as is recited in Claims 1 and 4, and as such, Claims 1 and 4 are in condition for allowance. Accordingly, Applicants also respectfully submit that Turnquist et al. does not anticipate or render obvious the present claimed invention as is recited in Claims 2 and 3 dependent on Claim 1, and Claims 5-7 dependent on Claim 4, and that Claims 2, 3 and 5-7 traverse the Examiners basis for rejection under 35 U.S.C. 103 as being dependent on an allowable base claim.

#### Conclusion

In light of the above-listed remarks, Applicants respectfully request allowance of the remaining Claims.

The Examiner is urged to contact Applicants' undersigned representative if the Examiner believes such action would expedite resolution of the present Application.

Respectfully submitted,

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